



(12) **CORRECTED EUROPEAN PATENT APPLICATION**

published in accordance with Art. 158(3) EPC

Note: Bibliography reflects the latest situation

(15) Correction information:

Corrected version no 1 (W1 A1)
INID code(s) 84

(51) Int Cl.:

H01S 5/068 (2006.01)

(48) Corrigendum issued on:

22.11.2006 Bulletin 2006/47

(86) International application number:

PCT/JP2004/006767

(43) Date of publication:

08.02.2006 Bulletin 2006/06

(87) International publication number:

WO 2004/102754 (25.11.2004 Gazette 2004/48)

(21) Application number: **04732770.5**

(22) Date of filing: **13.05.2004**

(84) Designated Contracting States:

DE FR GB IT

(30) Priority: **13.05.2003 JP 2003135168**

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(54) **OPTICAL MODULE AND ITS WAVELENGTH MONITOR CONTROL METHOD**

(57) The present invention provides wavelength monitoring and/or control enabling size reduction and low power operation without requiring a complicated optical system in its wavelength monitoring and controlling mechanism.

The measurement portion (1) measures temperature by a thermistor (5) in the measurement portion, and measures a bias current by using an LD drive current detecting circuit (6). The LD temperature, optical output and bias current are measured by the measurement portion. The relationship between the LD temperature and wavelengths or between the temperature, bias current and wavelengths is stored in a memory map of the storage portion (2). The central controlling portion (3) calculates wavelengths on the basis of the temperature and the bias current or the temperature information of the measurement portion, and the relationship between the LD temperature, bias current and wavelengths or between the temperature and wavelengths of the storage

portion.

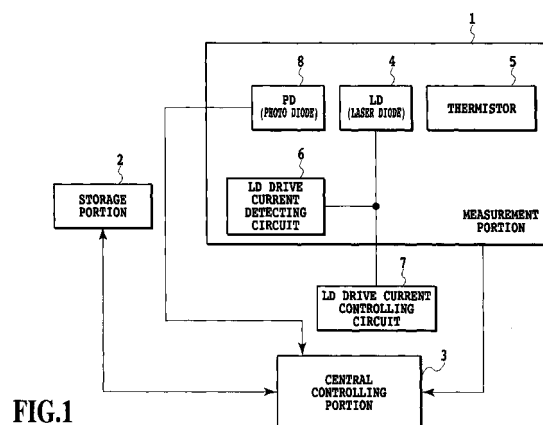


FIG.1